

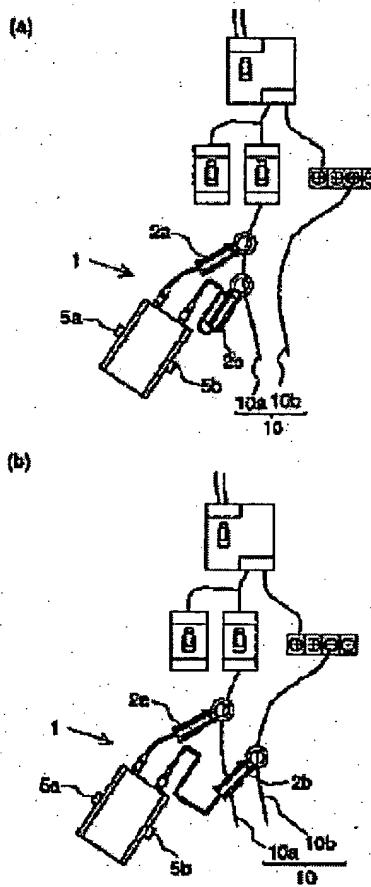
LEAK CURRENT PROBING DEVICE

Patent number: JP2002098729
Publication date: 2002-04-05
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Classification:
- **international:** G01R31/08; G01R15/18; G01R31/02
- **european:**
Application number: JP20000294550 20000927
Priority number(s): JP20000294550 20000927

Abstract of JP2002098729

PROBLEM TO BE SOLVED: To detect surely a leak current by compensating errors in spite of existence of the detection errors and the difference between detection accuracies of two current detection means, and to improve workability of a clamp in a probing work.

SOLUTION: Two current detection parts 2a, 2b are clamped simultaneously on the same voltage phase wiring route 10a, and the difference between each current value detected from the two current detection parts 2a, 2b is operated by a difference operation part 6, and adjustment is executed so as to remove the difference and to square each current value by adjustment parts 5a, 5b, and then, while one current detection part 2a is clamped on the voltage phase wiring route as it is, the other current detection part 2b is clamped on the earthing wire side and the difference is detected. Therefore, a probing action can be executed in the state where mutual errors are adjusted and squared so as to be compensated each other, and existence of the leak can be judged from the difference of the relative detection.



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